



3.3V CMOS 16-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS, 5 VOLT TOLERANT I/O, BUS-HOLD

IDT74LVCH16952A

FEATURES:

- Typical $t_{sk(o)}$ (Output Skew) < 250ps
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model ($C = 200\text{pF}$, $R = 0$)
- $V_{CC} = 3.3V \pm 0.3V$, Normal Range
- $V_{CC} = 2.7V$ to $3.6V$, Extended Range
- CMOS power levels ($0.4\mu\text{W}$ typ. static)
- All inputs, outputs, and I/O are 5V tolerant
- Supports hot insertion
- Available in SSOP, TSSOP, and TVSOP packages

DRIVE FEATURES:

- High Output Drivers: $\pm 24\text{mA}$
- Reduced system switching noise

APPLICATIONS:

- 5V and 3.3V mixed voltage systems
- Data communication and telecommunication systems

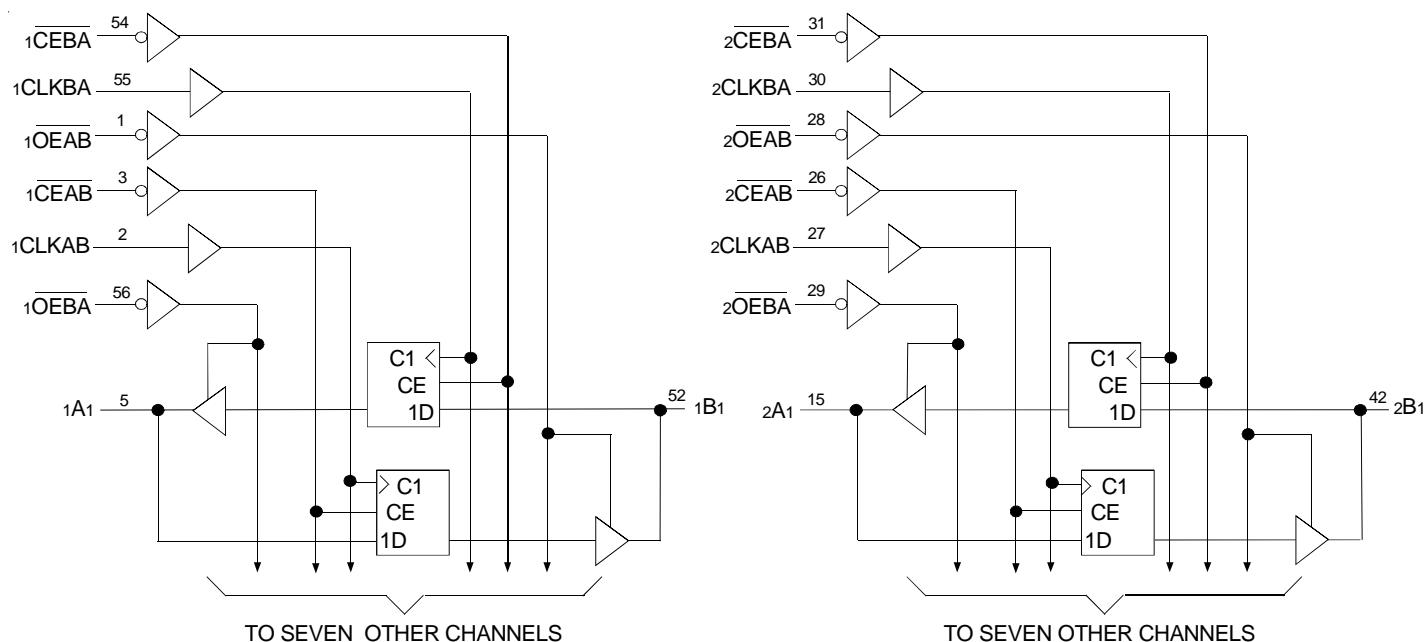
DESCRIPTION:

This 16-bit registered transceiver is built using advanced dual metal CMOS technology. This high-speed, low power device is organized as two independent 8-bit D-type registered transceivers with separate input and output control for independent control of data flow in either direction. For example, the A-to-B Enable (\overline{CEAB}) must be LOW to enter data from the A port. $CLKAB$ controls the clocking function. When $CLKAB$ toggles from LOW-to-HIGH, the data present on the A port will be clocked into the register. $OEAB$ performs the output enable function on the B port. Data flow from the B port to A port is similar but requires using \overline{CEBA} , $CLKBA$, and \overline{OEBA} inputs. Full 16-bit operation is achieved by tying the control pins of the independent transceivers together.

All pins can be driven from either 3.3V or 5V devices. This feature allows the use of this device as a translator in a mixed 3.3V/5V supply system.

The LVCH16952A has "bus-hold" which retains the inputs' last state whenever the input goes to a high impedance. This prevents floating inputs and eliminates the need for pull-up/down resistors.

FUNCTIONAL BLOCK DIAGRAM



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INDUSTRIAL TEMPERATURE RANGE

PIN CONFIGURATION

1OEAB		1	56		1OEBA
1CLKAB		2	55		1CLKBA
1CEAB		3	54		1CEBA
GND		4	53		GND
1A1		5	52		1B1
1A2		6	51		1B2
Vcc		7	50		Vcc
1A3		8	49		1B3
1A4		9	48		1B4
1A5		10	47		1B5
GND		11	46		GND
1A6		12	45		1B6
1A7		13	44		1B7
1A8		14	43		1B8
2A1		15	42		2B1
2A2		16	41		2B2
2A3		17	40		2B3
GND		18	39		GND
2A4		19	38		2B4
2A5		20	37		2B5
2A6		21	36		2B6
Vcc		22	35		Vcc
2A7		23	34		2B7
2A8		24	33		2B8
GND		25	32		GND
2CEAB		26	31		2CEBA
2CLKAB		27	30		2CLKBA
2OEAB		28	29		2OEBA

SSOP/ TSSOP/ TVSOP
TOP VIEW

CAPACITANCE ($T_A = +25^\circ\text{C}$, $F = 1.0\text{MHz}$)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C_{IN}	Input Capacitance	$V_{IN} = 0V$	4.5	6	pF
C_{OUT}	Output Capacitance	$V_{OUT} = 0V$	6.5	8	pF
$C_{I/O}$	I/O Port Capacitance	$V_{IN} = 0V$	6.5	8	pF

NOTE:

1. As applicable to the device type.

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Description	Max	Unit
V_{TERM}	Terminal Voltage with Respect to GND	-0.5 to +6.5	V
T_{STG}	Storage Temperature	-65 to +150	°C
I_{OUT}	DC Output Current	-50 to +50	mA
I_{IK}	Continuous Clamp Current, $V_I < 0$ or $V_O < 0$	-50	mA
I_{CC}	Continuous Current through each Vcc or GND	±100	mA
I_{SS}			

NOTE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

PIN DESCRIPTION

Pin Names	Description
$x\bar{OEAB}$	A-to-B Output Enable Inputs (Active LOW)
$x\bar{OEBA}$	B-to-A Output Enable Inputs (Active LOW)
$x\bar{CEAB}$	A-to-B Clock Enable Inputs (Active LOW)
$x\bar{CEBA}$	B-to-A Clock Enable Inputs (Active LOW)
$xCLKAB$	A-to-B Clock Inputs
$xCLKBA$	B-to-A Clock Inputs
xAx	A-to-B Data Inputs or B-to-A 3-State Outputs ⁽¹⁾
xBx	B-to-A Data Inputs or A-to-B 3-State Outputs ⁽¹⁾

NOTE:

1. These pins have "Bus-Hold". All other pins are standard inputs, outputs, or I/Os.

FUNCTION TABLE^(1,2)

Inputs				Outputs
$xCEAB$	$xCLKAB$	$x\bar{OEAB}$	xAx	xBx
H	X	L	X	$B^{(3)}$
X	L	L	X	$B^{(3)}$
L	↑	L	L	L
L	↑	L	H	H
X	X	H	X	Z

NOTES:

1. A-to-B data flow is shown: B-to-A data flow is similar but uses $x\bar{CEBA}$, $xCLKBA$, and $x\bar{OEBA}$.
2. H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High Impedance
↑ = LOW-to-HIGH Transition
3. Output level of B before the indicated steady-state input conditions were established.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition: TA = -40°C to +85°C

Symbol	Parameter	Test Conditions		Min.	Typ. ⁽¹⁾	Max.	Unit
VIH	Input HIGH Voltage Level	VCC = 2.3V to 2.7V		1.7	—	—	V
		VCC = 2.7V to 3.6V		2	—	—	
VIL	Input LOW Voltage Level	VCC = 2.3V to 2.7V		—	—	0.7	V
		VCC = 2.7V to 3.6V		—	—	0.8	
I _{IH} I _{IL}	Input Leakage Current	VCC = 3.6V	V _I = 0 to 5.5V	—	—	±5	µA
I _{OZH} I _{OZL}	High Impedance Output Current (3-State Output pins)	VCC = 3.6V	VO = 0 to 5.5V	—	—	±10	µA
I _{OFF}	Input/Output Power Off Leakage	VCC = 0V, V _{IN} or V _O ≤ 5.5V		—	—	±50	µA
V _{IK}	Clamp Diode Voltage	VCC = 2.3V, I _{IN} = -18mA		—	-0.7	-1.2	V
V _H	Input Hysteresis	VCC = 3.3V		—	100	—	mV
I _{CCL} I _{CCH} I _{CCZ}	Quiescent Power Supply Current	VCC = 3.6V	V _{IN} = GND or VCC	—	—	10	µA
			3.6 ≤ V _{IN} ≤ 5.5V ⁽²⁾	—	—	10	
ΔI _{CC}	Quiescent Power Supply Current Variation	One input at VCC - 0.6V, other inputs at VCC or GND		—	—	500	µA

NOTES:

1. Typical values are at VCC = 3.3V, +25°C ambient.

2. This applies in the disabled state only.

BUS-HOLD CHARACTERISTICS

Symbol	Parameter ⁽¹⁾	Test Conditions		Min.	Typ. ⁽²⁾	Max.	Unit
I _{BHH} I _{BHL}	Bus-Hold Input Sustain Current	VCC = 3V	V _I = 2V	-75	—	—	µA
			V _I = 0.8V	75	—	—	
I _{BHH} I _{BHL}	Bus-Hold Input Sustain Current	VCC = 2.3V	V _I = 1.7V	—	—	—	µA
			V _I = 0.7V	—	—	—	
I _{BHHO} I _{BHLO}	Bus-Hold Input Overdrive Current	VCC = 3.6V	V _I = 0 to 3.6V	—	—	±500	µA

NOTES:

1. Pins with Bus-Hold are identified in the pin description.

2. Typical values are at VCC = 3.3V, +25°C ambient.

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Max.	Unit
VOH	Output HIGH Voltage	VCC = 2.3V to 3.6V	I _{OH} = - 0.1mA	VCC - 0.2	—	V
		VCC = 2.3V	I _{OH} = - 6mA	2	—	
		VCC = 2.3V	I _{OH} = - 12mA	1.7	—	
		VCC = 2.7V		2.2	—	
		VCC = 3V		2.4	—	
		VCC = 3V	I _{OH} = - 24mA	2	—	
VOL	Output LOW Voltage	VCC = 2.3V to 3.6V	I _{OL} = 0.1mA	—	0.2	V
		VCC = 2.3V	I _{OL} = 6mA	—	0.4	
			I _{OL} = 12mA	—	0.7	
		VCC = 2.7V	I _{OL} = 12mA	—	0.4	
		VCC = 3V	I _{OL} = 24mA	—	0.55	

NOTE:

1. V_{IH} and V_{IL} must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate V_{cc} range.
TA = - 40°C to + 85°C.

OPERATING CHARACTERISTICS, V_{CC} = 3.3V ± 0.3V, TA = 25°C

Symbol	Parameter	Test Conditions	Typical	Unit
CPD	Power Dissipation Capacitance per Transceiver Outputs enabled	CL = 0pF, f = 10Mhz	87	pF
CPD	Power Dissipation Capacitance per Transceiver Outputs disabled		43	

SWITCHING CHARACTERISTICS⁽¹⁾

Symbol	Parameter	V _{CC} = 2.7V		V _{CC} = 3.3V ± 0.3V		Unit
		Min.	Max.	Min.	Max.	
f _{MAX}		150	—	150	—	MHz
t _{PLH}	Propagation Delay xCLKAB, xCLKBA to xBx, xAx	—	7.6	1.6	6.6	ns
t _{PHZ}	Output Enable Time xOEBA, xOEAB to xAx, xBx	—	8	1.1	6.6	ns
t _{PLZ}	Output Disable Time xOEBA, xOEAB to xAx, xBx	—	7.1	1.9	6.7	ns
t _{SU}	Set-up Time, data before xCLKAB↑, xCLKBA↑	3.4	—	2.8	—	ns
t _H	Hold Time, data after xCLKAB↑, xCLKBA↑	0.5	—	0.5	—	ns
t _{SH}	Set-up Time, xCEAB, xCEBA before xCLKAB↑, xCLKBA↑	1.8	—	1.4	—	ns
t _{HD}	Hold Time, xCEAB, xCEBA after xCLKAB↑, xCLKBA↑	1.1	—	1.9	—	ns
t _W	Pulse Duration HIGH or LOW, xCLKAB or xCLKBA	3.3	—	3.3	—	ns
t _{SK(0)}	Output Skew ⁽²⁾	—	—	—	1	ns

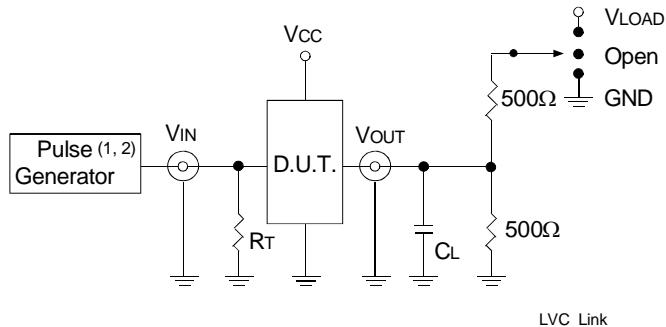
NOTES:

1. See TEST CIRCUITS AND WAVEFORMS. TA = - 40°C to + 85°C.
2. Skew between any two outputs of the same package and switching in the same direction.

TEST CIRCUITS AND WAVEFORMS

TEST CONDITIONS

Symbol	$V_{CC}^{(1)} = 3.3V \pm 0.3V$	$V_{CC}^{(1)} = 2.7V$	$V_{CC}^{(2)} = 2.5V \pm 0.2V$	Unit
V_{LOAD}	6	6	$2 \times V_{CC}$	V
V_{IH}	2.7	2.7	V_{CC}	V
V_T	1.5	1.5	$V_{CC} / 2$	V
V_{LZ}	300	300	150	mV
V_{HZ}	300	300	150	mV
C_L	50	50	30	pF



Test Circuit for All Outputs

DEFINITIONS:

C_L = Load capacitance: includes jig and probe capacitance.

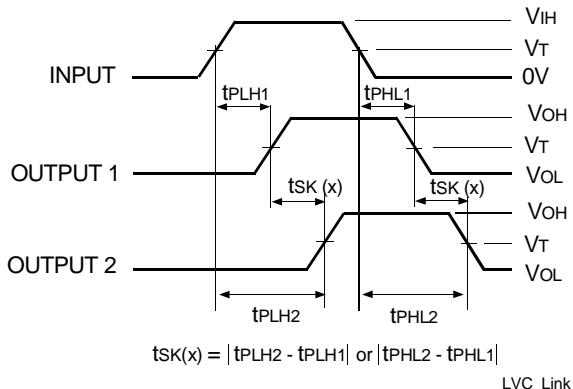
R_T = Termination resistance: should be equal to Z_{out} of the Pulse Generator.

NOTES:

1. Pulse Generator for All Pulses: Rate $\leq 10MHz$; $t_f \leq 2.5ns$; $t_r \leq 2.5ns$.
2. Pulse Generator for All Pulses: Rate $\leq 10MHz$; $t_f \leq 2ns$; $t_r \leq 2ns$.

SWITCH POSITION

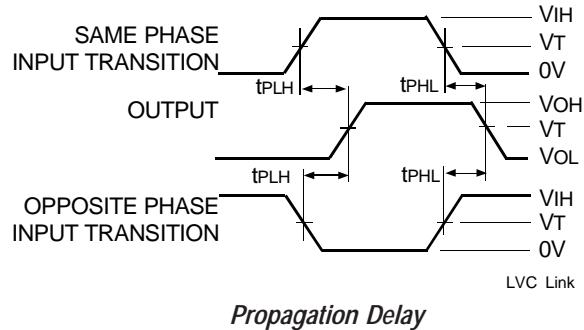
Test	Switch
Open Drain	V_{LOAD}
Disable Low	
Enable Low	
Disable High	GND
Enable High	
All Other Tests	Open



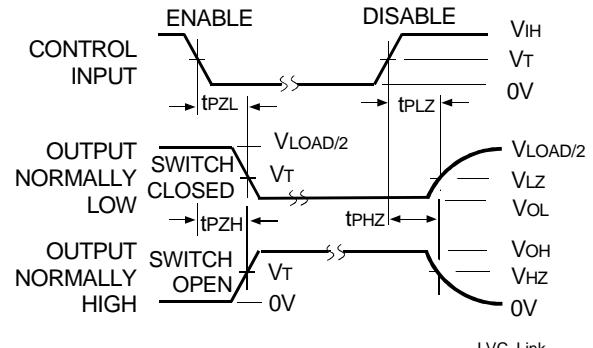
Output Skew - $t_{SK}(x)$

NOTES:

1. For $t_{SK}(o)$ OUTPUT1 and OUTPUT2 are any two outputs.
2. For $t_{SK}(b)$ OUTPUT1 and OUTPUT2 are in the same bank.



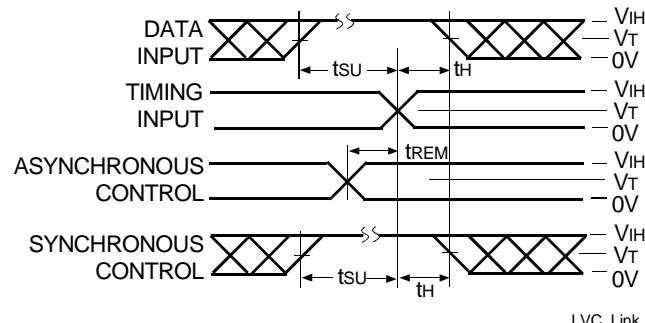
Propagation Delay



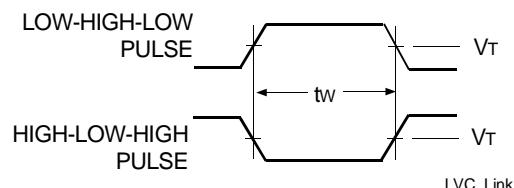
Enable and Disable Times

NOTE:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

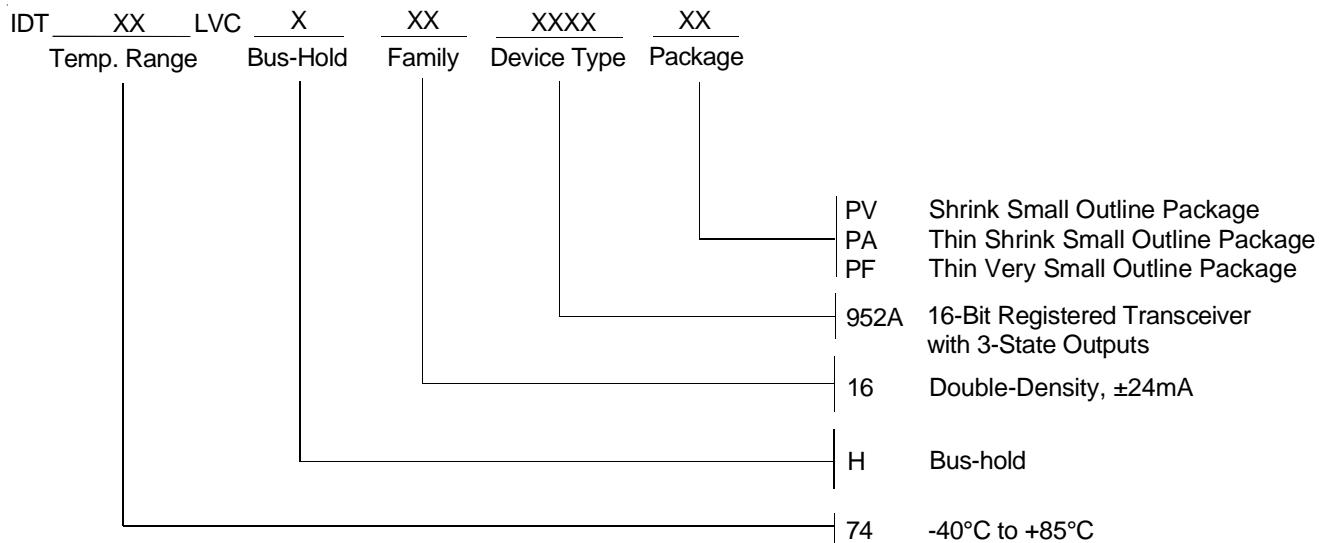


Set-up, Hold, and Release Times



Pulse Width

ORDERING INFORMATION



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